



**INTERNATIONAL
TEST CONFERENCE
2008**
Oct. 28 – Oct. 30, 2008
Santa Clara Convention Center
Santa Clara, California, USA

**CALL
FOR
POSTERS**

The Cornerstone of Test Week™

Test Week: Oct. 26 – Oct. 31, 2008

International Test Conference is the world's premier conference dedicated to the electronic test of devices, boards and systems—covering the complete cycle from design verification, test, diagnosis, failure analysis and back to process and design improvement. At ITC, test and design professionals can confront the challenges the industry faces, and learn how these challenges are being addressed by the combined efforts of academia, design tool and equipment suppliers, designers, and test engineers.

ITC, the cornerstone of the Test Week™ event, offers a wide variety of technical activities targeted at test and design theoreticians and practitioners, including: formal paper sessions, tutorials, panel sessions, case studies, lecture and application series, commercial exhibits and presentations, and a host of ancillary professional meetings.

Posters – A new way of participating in ITC

For 2008 we are initiating a **Poster Session**. Posters will be a part of the ITC **Wine and Cheese Reception** after Panels on Wednesday, October 29. Posters should be a single 20" by 30" sheet of poster board and a presentation on a presenter-supplied laptop. Presenters can also make a five-minute summary presentation of their material at a special session on Wednesday afternoon. Posters are a useful way of presenting late-breaking results, getting feedback on an innovative method, or participating without having to write a full paper. Acceptance as a poster does not preclude submission of a more complete treatment as an ITC paper in 2009.

Submissions must include:

- Title of poster.
- Name, affiliation, mailing address, e-mail address, phone and fax number of each author.
- Designation of the presenter(s). ITC will communicate with the presenter.
- One or two topic(s) from the topic list, or a description of your topic.
- An electronic copy of a one page summary of the poster, in PDF format. If the poster is accepted, this summary will be included in the ITC Proceedings CD.
- An abstract of 35 words or less.

Please note that the submission deadline is firm.

Submission Deadline: July 7, 2008

Author Notification: August 4, 2008

All one-page submissions must be in electronic format. Prospective authors should read the detailed instructions regarding formats and submission requirements for posters which are available on the ITC Web site at:

<http://www.itctestweek.org>

For further information, check the ITC Web page or contact:

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Conference Focus Topics

Adaptive Test
BIST or Embedded Test—Chip and Board
Bring-up Test and Silicon Debug
Design and Test for Reliability
Experiments and Case Studies
High-Speed Digital Test
Low-Cost Test/ATE
On-Chip Test Compression
On-line Test
RF Testing
Test Data Analysis
Test for Nanometer Technologies
Test Resource Partitioning

Hot Topics

Board and System Test
Defect-based Testing
High-Speed I/O Test
Innovative Industrial Test Practice
Power Issues in Test
Test and Design for Manufacturability
Volume Diagnosis and Yield Learning

Regular Topics:

ATE Hardware and Software
ATPG, Test Synthesis
Boundary-Scan
Design-for-Test: Chip, Board and System
Economics of Test
FPGA Test
IDDQ and Current Test
Interface Issues
Loadboard Design and Simulation
MCM and KGD Test
Memory Test
Microprocessor Test
Mixed-Signal and Analog Test
Multisite Test
Production Test Automation
System-on-Chip Test
System-in-Package Test
Test Standards
Test Effectiveness
Wafer Probe

